

TOSHIBA MOS MEMORY PRODUCTS

32,768 WORD×8 BIT STATIC RAM
SILICON GATE CMOS

TC55257APL-85/APL-10/APL-12
TC55257AFL-85/AFL-10/AFL-12

PRELIMINARY

DESCRIPTION

The TC55257APL/AFL is 262,144 bit static random access memory organized as 32,768 words by 8 bits using CMOS technology, and operated from a single 5V supply. Advanced circuit techniques provide both high speed and low power features with a operating current of 5mA/MHz (Typ.) and minimum cycle time of 85ns. When \overline{CE} is a logical high, the device is placed in low power standby mode in which standby current is $2\mu A$ typically. The TC55257 APL/AFL has two control inputs. Chip enable

(\overline{CE}) allow for device selection and data retention control, and an output enable input (\overline{OE}) provides fast memory access. Thus the TC55257APL/AFL is suitable for use in various microprocessor application systems where high speed, low power, and battery back up are required. The TC55257APL/AFL is offered in both a standard dual-in-line 28 pin plastic package (0.6 inch width) and small-out-line plastic flat package.

FEATURES

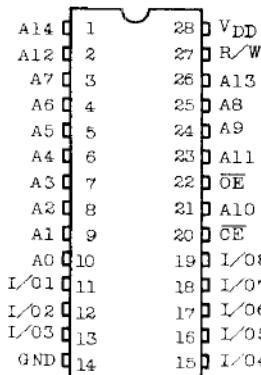
- Low Power Dissipation
27.5mW/MHz (Typ.) Operating
- Standby Current
 $100\mu A$ (Max.): TC55257APL-85/AFL-85
APL-10/AFL-10
APL-12/AFL-12
- 5V Single Power Supply
- Power Down Feature: \overline{CE}

- Data Retention Supply Voltage: 2.0 ~ 5.5V
- Access Time

	TC55257APL-85 TC55257AFL-85	TC55257APL-10 TC55257AFL-10	TC55257APL-12 TC55257AFL-12
Access Time (Max.)	85ns	100ns	120ns
Chip Enable Access Time (Max.)	85ns	100ns	120ns
Output Enable Time (Max.)	45ns	50ns	60ns

- Directly TTL Compatible: All Inputs and Outputs
- Plastic DIP and Plastic Flat Package

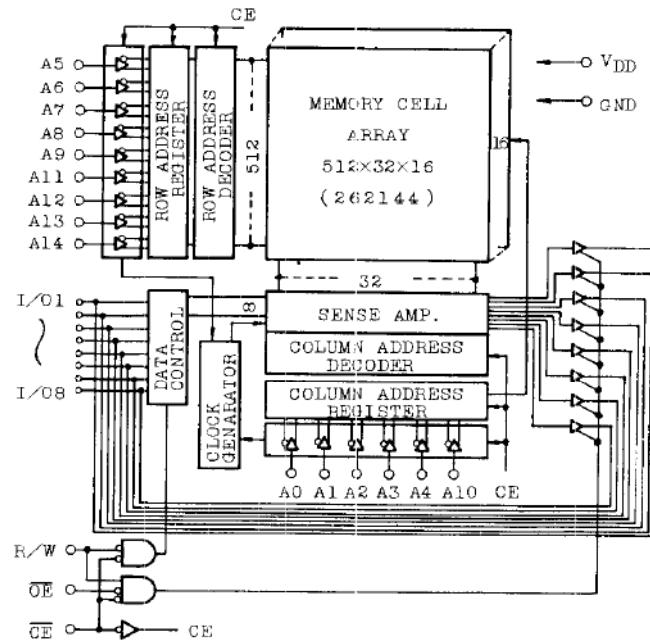
PIN CONNECTION (TOP VIEW)



PIN NAMES

A0 ~ A14	Address Inputs
R/W	Read/Write Control Input
OE	Output Enable Input
CE	Chip Enable Input
I/O1 ~ I/O8	Data Inputs/Outputs
V _{DD}	Power (+5V)
GND	Ground

BLOCK DIAGRAM



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TC55257AFL-85/AFL-10/AFL-12

OPERATION MODE

OPERATION MODE	CE	OE	R/W	I/01 ~ I/08	POWER
Read	L	L	H	D _{OUT}	I _{DD0}
Write	L	*	L	D _{IN}	I _{DD0}
Output Deselect	L	H	H	High-Z	I _{DD0}
Standby	H	*	*	High-Z	I _{DDS}

*) H or L

MAXIMUM RATINGS

SYMBOL	ITEM	RATING	UNIT
V _{DD}	Power Supply Voltage	-0.3 ~ 7.0	V
V _{IN}	Input Voltage	-0.3* ~ 7.0	V
V _{I/O}	Input and Output Voltage	-0.5 ~ V _{DD} + 0.5	V
P _D	Power Dissipation	1.0	W
T _{solder}	Soldering Temperature	260 ~ 10	°C·sec
T _{strg}	Storage Temperature	-55 ~ 150	°C
T _{opr}	Operating Temperature	0 ~ 70	°C

*) -3.0V at pulse width 50ns

D.C. RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
V _{DD}	Power Supply Voltage	4.5	5.0	5.5	V
V _{IH}	Input High Voltage	2.2	--	V _{DD} + 0.3	V
V _{IL}	Input Low Voltage	-0.3*	--	0.8	V
V _{DH}	Data Retention Supply Voltage	2.0	--	5.5	V

*) -3.0V at pulse width 50ns

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D.C. and OPERATING CHARACTERISTICS ($T_a = 0 \sim 70^\circ C$, $V_{DD} = 5V \pm 10\%$)

SYMBOL	PARAMETER	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
I_{IL}	Input Leakage Current	$V_{IN} = 0 \sim V_{DD}$	—	—	± 1.0	μA
I_{OH}	Output High Current	$V_{OH} = 2.4V$	-1.0	—	—	mA
I_{OL}	Output Low Current	$V_{OL} = 0.4V$	4.0	—	—	mA
I_{LO}	Output Leakage Current	$CE = V_{IH}$ or $R/W = V_{IL}$ or $OE = V_{IH}$ $V_{OUT} = 0 \sim V_{DD}$	—	—	± 1.0	μA
I_{DD01}	Operating Current	$V_{DD} = 5.5V$ $CE = V_{IL}$, $R/W = V_{IH}$ Other Input = V_{IH}/V_{IL} $I_{OUT} = 0mA$	$t_{cycle} = 1\mu s$	—	10	—
			$t_{cycle} =$ Min. cycle	—	70	mA
I_{DD02}		$V_{DD} = 5.5V$ $CE = 0.2V$, $R/W = V_{DD}-0.2V$ Other Input = $V_{DD}-0.2V/0.2V$ $I_{OUT} = 0mA$	$t_{cycle} = 1\mu s$	—	5	—
			$t_{cycle} =$ Min. cycle	—	60	mA
I_{DDS1}	Standby Current	$CE = V_{IH}$	—	—	3	mA
I_{DDS2}	Standby Current	$CE = V_{DD}-0.2V$ $V_{DD} = 2.0 \sim 5.5V$	$T_a = 0 \sim 70^\circ C$	—	2	100
						μA

CAPACITANCE ($T_a = 25^\circ C$, $f = 1MHz$)

SYMBOL	PARAMETER	TEST CONDITION	MAX.	UNIT
C_{IN}	Input Capacitance	$V_{IN} = GND$	10	pF
C_{OUT}	Output Capacitance	$V_{OUT} = GND$	10	pF

Note: This parameter periodically sampled is not 100% tested.

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A.C. CHARACTERISTICS (Ta = 0 ~ 70°C, V_{DD} = 5V ± 10%)

Read Cycle

SYMBOL	PARAMETER	TC55257APL-85 TC55257AFL-85		TC55257APL-10 TC55257AFL-10		TC55257APL-12 TC55257AFL-12		UNIT
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
t _{RC}	Read Cycle Time	85	—	100	—	120	—	ns
t _{ACC}	Address Access Time	—	85	—	100	—	120	
t _{CO}	CE Access Time	—	85	—	100	—	120	
t _{OE}	Output Enable to Output in Valid	—	45	—	50	—	60	
t _{COE}	Chip Enable (CE) to Output in Low-Z	10	—	10	—	10	—	
t _{OE}	Output Enable to Output in Low-Z	5	—	5	—	5	—	
t _{OD}	Chip Enable (CE) to Output in High-Z	—	30	—	50	—	60	
t _{ODO}	Output Enable to Output in High-Z	—	30	—	40	—	50	
t _{OH}	Output Data Hold Time	5	—	10	—	10	—	

Write Cycle

SYMBOL	PARAMETER	TC55257APL-85 TC55257AFL-85		TC55257APL-10 TC55257AFL-10		TC55257APL-12 TC55257AFL-12		UNIT
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
t _{WC}	Write Cycle Time	85	—	100	—	120	—	ns
t _{WP}	Write Pulse Width	60	—	70	—	80	—	
t _{CW}	Chip Selection to End of Write	65	—	90	—	100	—	
t _{AS}	Address Set up Time	0	—	0	—	0	—	
t _{WR}	Write Recovery Time	5	—	5	—	5	—	
t _{ODW}	R/W to Output High-Z	—	30	—	50	—	60	
t _{OEW}	R/W to Output Low-Z	10	—	10	—	10	—	
t _{DS}	Data Set up Time	40	—	40	—	50	—	
t _{DH}	Data Hold Time	0	—	0	—	0	—	

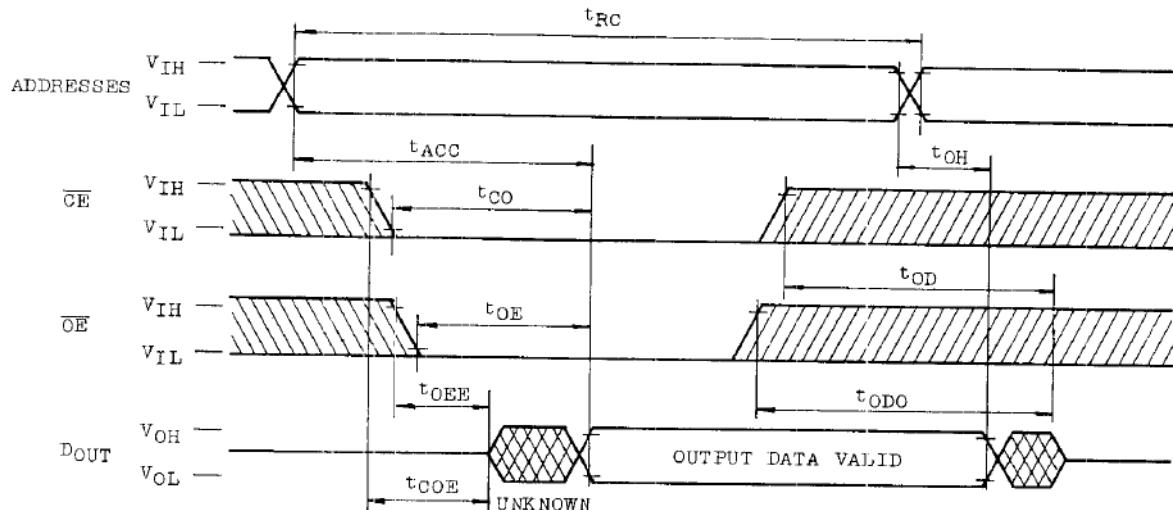
A.C. TEST CONDITIONS

Output Load : 100pF + 1TTL Gate
 Input Pulse Level : 0.6V, 2.4V
 Timing Measurement : 0.8V, 2.2V
 Reference Level : 0.8V, 2.2V
 t_r, t_f : 5ns

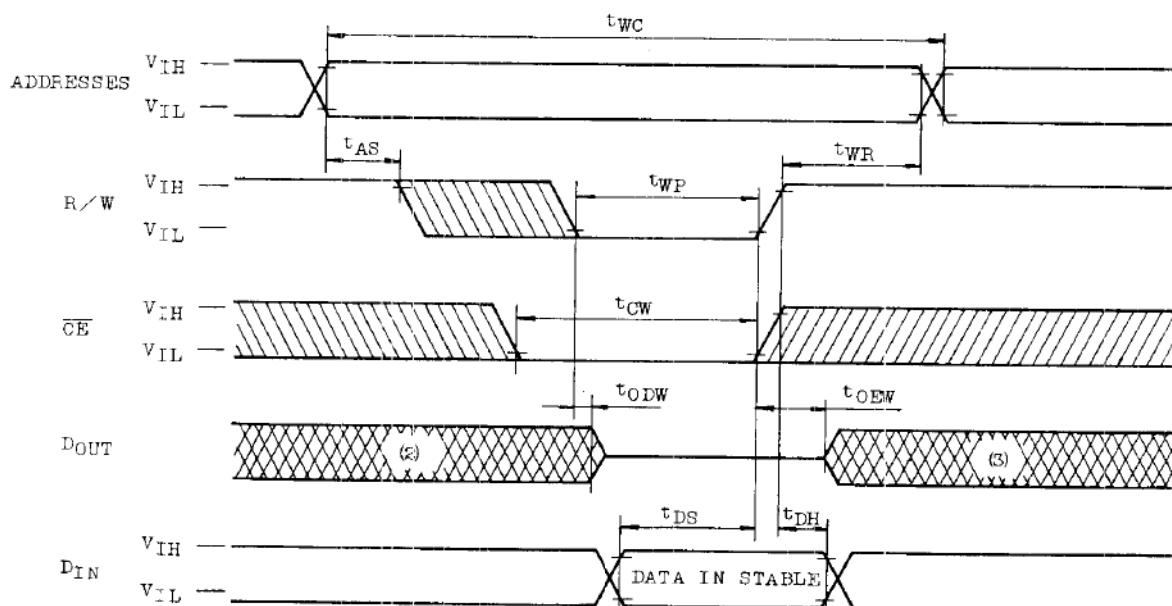
TC55257APL-85/APL-10/APL-12 TC55257AFL-85/AFL-10/AFL-12

TIMING WAVEFORMS

- READ CYCLE⁽¹⁾



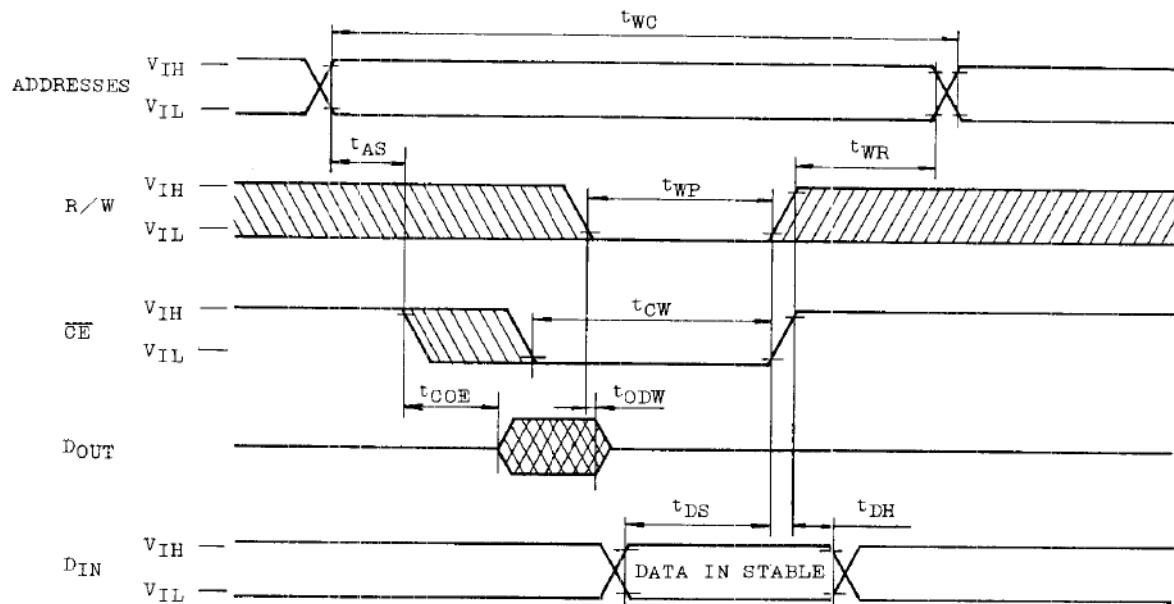
- WRITE CYCLE 1⁽⁴⁾ (R/W Controlled Write)



TC55257APL-85/APL-10/APL-12

TC55257AFL-85/AFL-10/AFL-12

- WRITE CYCLE 2⁽⁴⁾ (\overline{CE} Controlled Write)



- NOTE: 1. R/W is High for Read Cycle.
 2. Assuming that \overline{CE} low transition occurs coincident with or after R/W Low transition, Outputs remain in a high impedance state.
 3. Assuming that \overline{CE} High transition occurs coincident with or prior to R/W High transition, Output remain in a high impedance state.
 4. Assuming that \overline{OE} is High for Write Cycle, Outputs are in high impedance state during this period.

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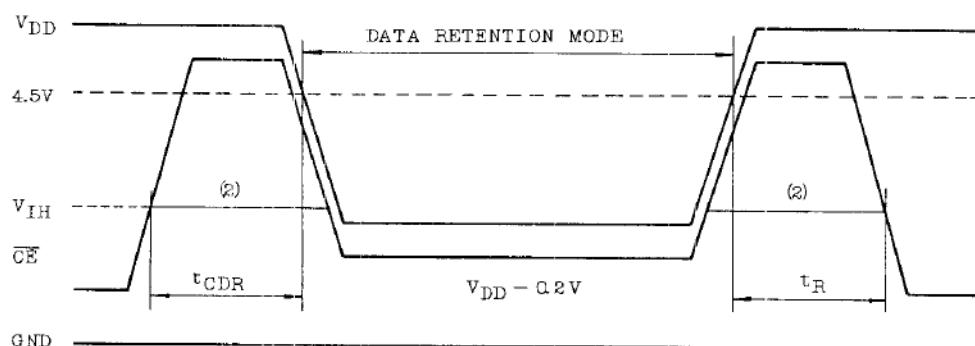
TC55257AFL-85/AFL-10/AFL-12

DATA RETENTION CHARACTERISTICS ($T_a = 0 \sim 70^\circ C$)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
V_{DH}	Data Retention Supply Voltage	2.0	—	5.5	V
I_{DDS2}	Standby Supply Current	$V_{DH} = 3.0V$	—	50	μA
		$V_{DH} = 5.5V$	—	100	
t_{CDR}	Chip Deselection to Data Retention Mode	0	—	—	μs
t_R	Recovery Time	$t_{RC(1)}$	—	—	

Note (1): Read Cycle Time.

- CE Controlled Data Retention Mode



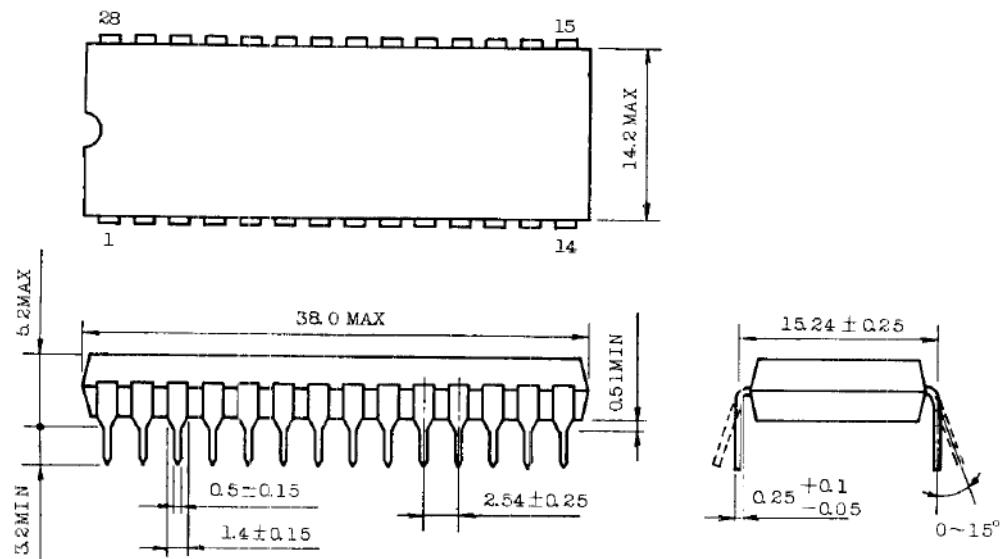
NOTE (2): If the V_{IH} of \overline{CE} is 2.2V in operation, I_{DDS1} current flows during the period that the V_{DD} voltage is going down from 4.5V to 2.4V.

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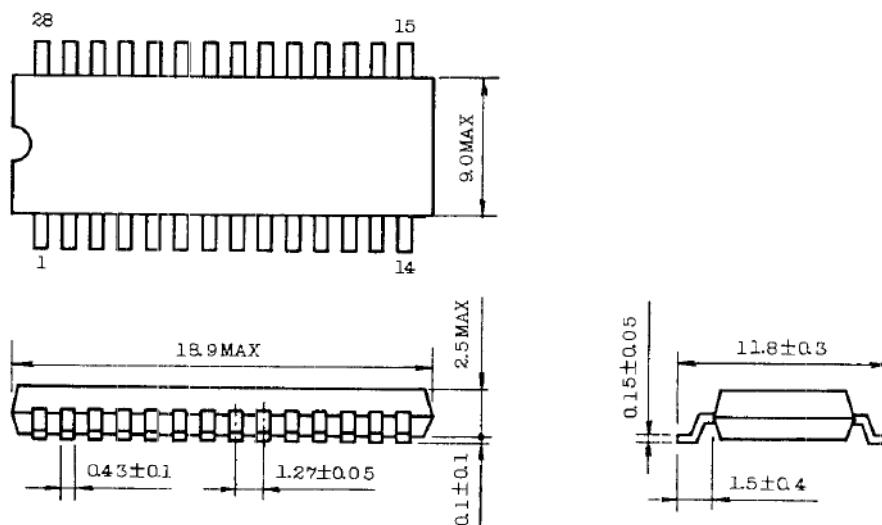
• DIP 28 PIN OUTLINE DRAWING (6D28A-P)

Unit in mm



NOTE: Lead pitch is 2.54 and tolerance is ± 0.25 against theoretical center of each lead that is obtained on the basis of No.1 and No.28 leads.

• MFP 28 PIN OUTLINE DRAWING (F28GA-P)



NOTE: Lead pitch is 1.27 and tolerance is ± 0.12 against theoretical center of each lead that is obtained on the basis of No.1 and No.28 leads.